

MAG – IRS Monitoring

Interferometer Alignment Monitoring

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IRS Alignment Monitoring

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Introduction

IRS = Fourier Transform Interferometer

Light enters an interferometer :





Geo-localised spectra are recovered from the interferogram by Fourier Transform:

$$S(v) = \int_{-OPD_m}^{OPD_m} Interf(x) e^{2i\pi vx} dx$$





Spectrum Generation

• From ECMWF simulation over North Atlantic (clear sky) to a calibrated spectrum



- Simplified processing for the study,
- Using representative parameters in line with the last updates by the industry (transmission, noise)



Spectrum Generation/ Misalignment

Perfect Alignment (Simulation with laser @ 4.5µm):

 $I(x) = 1 - \cos[2\pi\nu\,\cos(\theta)\,x\,]$

Angular MCC misalignments (or back optics optical axis drift) :



$$I(x) = 1 - \cos[2\pi\nu \,\cos(\theta - \Delta\theta) \,x\,]$$

On-axis and off-axis FCC translation:

$$I(x) = 1 - \cos[2\pi\nu \{x - x_{ZPD} - x_{YZ0}(\theta)\}$$

$$x_{YZ0} = Y0\sin(\theta_y) + Z0\sin(\theta_z)$$





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Spectra Scale Factors

I) Angular Misalignment

• The cosine factor rescales the spectrum in the field:

The IRS uses a **3-laser metrology** system that corrects the rescaling at the interferogram level

• However, misalignment in the back telescope and cold optics could still occur after the launch:

$$S_{metro}(\nu,\theta) = S\left[\nu \times \frac{\cos(\theta - \Delta\theta)}{\cos(\theta)}\right] \cong S[\nu (1 - \vec{\theta}. \vec{\Delta\theta})]$$

 $I(x) = 1 - \cos[2\pi v \cos(\theta)x] \rightarrow TF[I(x)] = S(v,\theta) = S[v \times \cos(\theta)]$

Specification gives : $\Delta \theta < \frac{10^{-6}}{\theta} = 28 \mu rad$

• And, focal plane defocus: $S_{metro}(v,\theta) = S\left[v \times \frac{\cos(\theta')}{\cos(\theta)}\right] \cong S[v \times (1 - \theta^2 \frac{\delta f'}{f'})]$ Specification gives : $\delta f'/f' < \frac{10^{-6}}{\theta^2} = 0.08\%$!

So the angular alignment and focal plane defocus have to be monitored and the spectra rescaled !





SFs

Scale Factor Fitting

- In-line processing :
 - Scale factor determination for all pixels independently using spectral features positions for spectra over North Atlantic (every 20min)
 - Scale factor prediction using the last few measurements
 - Spectra correction : Precision = 1ppm
- Off-line monitoring:
 - Scale factor fitting over the full detector to extract the physical misalignment.
 - → Circular effect : focal plane defocus
 - → Slope : angular misalignment
 - Incredibly accurate parameters retrieval :

 $\sigma\Delta\theta$ = 0.4 μ rad $\sigma(\delta f'/f')$ = 2.2 10^{-5}



Ex: $\Delta \theta_y = 90 \mu \text{rad}, \ \delta f' / f' = 0.2\%$, with IRS Representative noise, LWIR MICOS



FCC shifts Product quality impact

II) Fixed Corner Cube Shifts

• FCC displacements shift the interferogram: $I(x) = 1 - cos[2\pi v \{x - x_{ZPD} - x_{YZ0}(\theta)\}]$ and produce a phase proportional to the wave number:

$$\tilde{S}(v) = \int_{-OPD_m}^{OPD_m} I(x - \delta x) e^{2i\pi v x} dx \cong \int_{-OPD_m}^{OPD_m} I(x) e^{2i\pi v (x + \delta x)} dx$$
$$= S(v) e^{2i\pi v \delta x}$$
With, $\delta x = x_{ZPD} + Y0 \sin(\theta_y) + Z0 \sin(\theta_z)$ On-axis Off-axis



- If the FCC shift is constant, then this effect is cancelled with the complex radiometric calibration realized with the black body and deep space views on-board.
- Moreover, the metrology system cancel most of it calculating the difference of positions between MCC and FCC at any time.
- However, if the ZPD is fluctuating between two radiometric calibrations, and the metrology fail to correct every movement, then the real part product can be **noisy and biased** !



FCC shifts Product quality impact

- The real product amplitude is related to the FCC shifts:

$$Real\left(\tilde{S}(\nu)\right) \cong S(\nu)\cos(2\pi\nu\delta x) \cong S(\nu)\left[1-\frac{(2\pi\nu\delta x)^2}{2}\right]$$

- The vibration can first bias the product :

Bias = 0.1% for $\sigma_{\delta x} \cong 32$ (MWIR), 100(LWIR)nm

- The vibrations will also produce a noise, it would be equal to the expected radiometric noise for:

 $\text{SNR}_{\text{rad}} = \text{SNR}_{\text{vib}} \rightarrow \sigma_{\delta x} \cong 100 \text{[MWIR]}, 200 \text{[LWIR]nm}$

- Both longitudinal and transversal vibrations are accounted : $\delta x = x_{ZPD} + Y0 \sin(\theta_y) + Z0 \sin(\theta_z)$, But transversal shifts contribute only in the field and since : $\sin(\theta_{max} = 2^o) = 0.035$ the interferometer is at least 25 times less sensible to transverse vibrations.

Goal : Monitor at the nm level the Corner Cube alignment !



Spectrum Phase Monitoring

- Product $\tilde{S}(v) = S(v) e^{2i\pi v \delta x}$ phase gradient study:
 - Compute the spectrum phase: $\varphi(v) = \operatorname{atan}[Im\{\tilde{S}(v)\}/Re\{\tilde{S}(v)\}]$
 - Phase linear fitting (weighted with spectrum amplitude): $2\pi \times (A0 + A1 \times \nu) = \text{LeastSquareFit}[\delta \varphi(\nu), Re{\tilde{S}(\nu)}]$
 - Spectrum dephasing correction (if necessary, not in the baseline): $S(v) = \tilde{S}(v) \times \exp(-2i\pi [A0 + A1 \times v])$
- With : $A1 = x_{ZPD} + Y0 \sin(\theta_y) + Z0 \sin(\theta_z)$ **I PGs PGs PGs**

NB : With IRS expected radiometric noise, A1 is retrieved at 2nm (MWIR) and 3.3nm (LWIR).



IRS representative example of phase fitting for a 50nm ZPD shift

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Spectrum Phase Monitoring

In-line processing :

Flag dwells with high phase gradients

Off-line processing :

- Looking at the measured phase gradients for all pixels
 - Constant component = FCC longitudinal shifts
 - Slope component = FCC transverse shifts
- Fitting over all detector give the FCC shifts monitoring at sub-nanometer level:
 - σx_{ZPD} = 14pm (MWIR), 28pm (LWIR)
 - $\sigma YZ0 = 0.8$ nm (MWIR), 1.5 nm (LWIR)
- Chromatism effect as a ZPD (v, θ) ? (Waiting for first instrument data)
 - Could be taken into account adding orders in the phase fittings and/or phase gradient fit (decreasing a bit the accuracy)
 - And chromatism could then be also monitored





FCC vibrations on IASI ?

• Study with IASI-b black body measurements show greater noise for the imaginary component than for the real as expected since the imaginary part is more sensitive to small shifts:

 $\rightarrow Real\left(\tilde{S}(\nu)\right) \cong S(\nu) \cos(2\pi\nu\delta x) \cong S(\nu) \left[1 - \frac{(2\pi\nu\delta x)^2}{2}\right]$ (Second order perturbation) $\rightarrow Imag\left(\tilde{S}(\nu)\right) \cong S(\nu) \sin(2\pi\nu\delta x) \cong S(\nu) \times (2\pi\nu\delta x)$ (First order perturbation) \leftarrow More Sensitive !

- Applying the residual phase correction, it equalize the real and imaginary noise to the radiometric noise.
 - Red curve (right vertical axis) the standard deviation of the real part.
 - Blue curves (right vertical axis) the standard deviation of the imaginary part.



Cyan curves (right vertical axis) the reference IASI noise from level 1c Black body spectra.



- We can evaluate the ZPD drift RMS for IASI-b : $\sigma_{\delta x} IASI \cong 3.5$ nm,
 - -> 12.7nm expected on IRS (IA Optical Analysis Report, MTG-TAS-F-IR-TN-1489)

Conclusion

Performances:

• Using fit over IRS full detectors lead to incredibly accurate alignment monitoring:

Method	Parameter	Accuracy
Scale Factor :	$\Delta heta$	0.4µrad
	$\delta f'/f'$	2.2 10 ⁻⁵
Phase gradient :	x _{ZPD}	14-28pm
	YZ0	0.8-1.5nm

• Great interest for long-term stability studies, warning of dangerous drifts (both for EUM and industry)

Open questions:

- Polynomial phase fitting could be implemented to track fluctuating chromatism ?
- Spectra are dynamically rescaled but their residual phase is not corrected yet.

Conclusion

MAG - Conclusion :

- Development of two off-line modules for the angular misalignment and FCC drifts monitoring and physical parameters retrieval,
- Further study on this topic could only be conducted with instrument data (chromatism, vibration ?)
- EUM team pursues the study of every defects that could deteriorate the data quality.